

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill  
Serial No. :  
Filed : June 24, 2003  
Title : INTERFEROMETRIC STAGE METROLOGY SYSTEM

Art Unit : Unknown  
Examiner : Unknown

**BOX PATENT APPLICATION**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

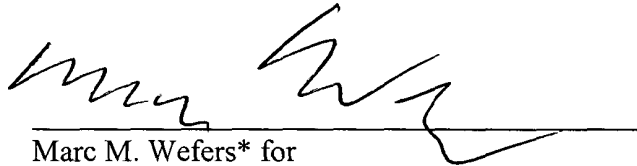
Applicant submits copies of references AA, AD, AE, AG and AK listed on the attached form PTO-1449. Copies of the remaining listed references have been submitted to or cited by the Office in the parent application and are therefore not provided.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date:

6/24/03



Marc M. Wefers\* for  
David L. Feigenbaum  
Reg. No. 30,378

Fish & Richardson P.C.  
225 Franklin Street  
Boston, MA 02110-2804  
Telephone: (617) 542-5070  
Facsimile: (617) 542-8906

**\*See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).**

20679727.doc

CERTIFICATE OF MAILING BY EXPRESS MAIL

Express Mail Label No. EV 330506301 US

June 24, 2003  
Date of Deposit

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-251003	Application No.
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Henry A. Hill	
		Filing Date June 24, 2003	Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,114,234	5/1992	Otsuka et al.	356	500	
	AB	5,151,749	9/29/1992	Tanimoto et al.			
	AC	5,187,543	2/16/1993	Ebert			
	AD	5,363,196	11/8/1994	Cameron	356	358	
	AE	5,764,361	6/9/1998	Kato et al.			
	AF	5,790,253	8/4/1998	Kamiya			
	AG	6,020,964	2/2000	Loopstra et al.	356	500	
	AH	6,134,007	10/2000	Naraki et al.	356	358	
	AI						
	AJ						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AK	JP 10260009 A	9/1998	Japan				
	AL							
	AM							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AN	
	AO	
	AP	
	AQ	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	